

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:	)	Confirmation No.: 5721
Hidekazu MIYAIRI et al.	)	Examiner: Jeffrey R. West
Serial No.: 10/808,499	)	Group Art Unit: 2857
Filed: March 25, 2004	)	
For: METHOD FOR TESTING	)	
SEMICONDUCTOR FILM,	)	
SEMICONDUCTOR DEVICE AND	)	
MANUFACTURING METHOD	)	
THEREOF	)	

**AMENDMENT**

Honorable Commissioner of Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In response to the Official Action dated January 28, 2010, the Interview Summary mailed March 23, 2010, and the Advisory Action dated May 25, 2010, and further to the After Final Response filed April 27, 2010, please consider the following amendments and remarks in connection with the above-identified application.

**Amendments to the Claims** are reflected in the listing of claims, which begins on page 2 of this paper.

**Remarks** begin on page 11 of this paper.